

IGBT3 Power Chip

Features:

- 1700V Trench + Field stop technology
- low switching losses and saturation losses
- soft turn off
- positive temperature coefficient
- easy paralleling

This chip is used for:

• power modules

Applications:

drives



| Chip Type | V _{CE} | <i>I</i> _C | Die Size | Package |
|----------------|------------------------|-----------------------|-------------------------------|--------------|
| IGC168T170S8RH | 1700V | 150A | 13.38 x 12.58 mm ² | sawn on foil |

Mechanical Parameters

| Mechanical i aramet | 010 | - | | | |
|-------------------------|----------------------------------|--|----|--|--|
| Raster size | | 13.38 x 12.58 | | | |
| Emitter pad size (incl. | gate pad) | 11.159 x 10.353 1.674 x 0.899 | | | |
| Gate pad size | | | | | |
| Area total | | 168.3 | | | |
| Thickness | | 190 | μm | | |
| Wafer size | | 200 | mm | | |
| Max.possible chips pe | er wafer | 142 | | | |
| Passivation frontside | | Photoimide | | | |
| Pad metal | | 3200 nm AlSiCu | | | |
| Backside metal | | Ni Ag –system suitable for epoxy and soft solder die bonding | | | |
| Die bond | | Electrically conductive glue or solder | | | |
| Wire bond | | Al, <500μm | | | |
| Reject ink dot size | | Ø 0.65mm ; max 1.2mm | | | |
| Otana and in a second | for original and sealed MBB bags | Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month | | | |
| Storage environment | for open MBB bags | Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert gas, Humidity <25%RH, Temperature 17°C – 25°C, < 6 month | | | |



Maximum Ratings

| Parameter | Symbol | Value | Unit | |
|--|--|----------|------|--|
| Collector-Emitter voltage, T_{vj} =25 °C | V _{CE} | 1700 | V | |
| DC collector current, limited by $T_{\rm vj\;max}$ | I _C | 1) | А | |
| Pulsed collector current, t_p limited by $T_{vj max}$ | $I_{c,puls}$ | 450 | Α | |
| Gate emitter voltage | V _{GE} | ±20 | V | |
| Junction temperature range | T _{vj} | -40 +175 | °C | |
| Operating junction temperature | $T_{\rm vj}$ | -40+150 | °C | |
| Short circuit data ²⁾ $V_{GE} = 15V$, $V_{CC} = 1000V$, $T_{vj} = 150$ °C | t_{SC} | 10 | μs | |
| Reverse bias safe operating area ²⁾ (RBSOA) | $I_{C,max} = 300A, V_{CE,max} = 1700V$ $T_{vj} \le 150 ^{\circ}C$ | | | |

¹⁾ depending on thermal properties of assembly

Static Characteristics (tested on wafer), T_{vj} =25 °C

| Parameter | Symbol | Conditions | Value | | | Unit |
|--------------------------------------|----------------------------------|--|-------|------|------|------|
| i didiletei | | | min. | typ. | max. | |
| Collector-Emitter breakdown voltage | V _{(BR)CES} | $V_{\rm GE}$ =0V , $I_{\rm C}$ = 2 mA | 1700 | | | |
| Collector-Emitter saturation voltage | V _{CEsat} ³⁾ | V _{GE} =15V, I _C =150A | 1.55 | 1.85 | 2.15 | V |
| Gate-Emitter threshold voltage | $V_{\rm GE(th)}$ | $I_{\rm C}$ =6mA , $V_{\rm GE}$ = $V_{\rm CE}$ | 5.2 | 5.8 | 6.4 | |
| Zero gate voltage collector current | I _{CES} | V _{CE} =1700V , V _{GE} =0V | | | 8 | μA |
| Gate-Emitter leakage current | I _{GES} | V_{CE} =0V , V_{GE} =20V | | | 300 | nA |
| Integrated gate resistor | $r_{\rm G}$ | | | 5 | | Ω |

³⁾ Vcesat tested at lower current

Dynamic Characteristics (not subject to production test - verified by design / characterization), T_{vj} =25 °C

| Parameter | Symbol | Conditions | Value | | | Unit |
|------------------------------|------------------|-------------------------|-------|-------|------|-------|
| raiailletei | Syllibol | Conditions | min. | typ. | max. | Oilit |
| Input capacitance | Cies | V _{CE} =25V, | | 13500 | | pF |
| Reverse transfer capacitance | C _{res} | $V_{GE}=0V$, f=1MHz | | 430 | | |

²⁾ not subject to production test - verified by design/characterization

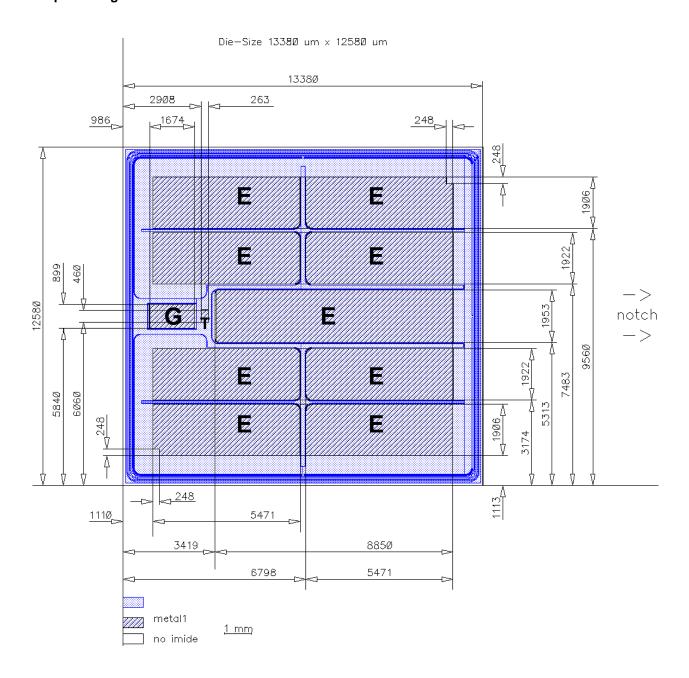


Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing



E = Emitter

G = Gate

T = Test pad do not contact



IGC168T170S8RH

| Description |
|---|
| AQL 0,65 for visual inspection according to failure catalogue |
| Electrostatic Discharge Sensitive Device according to MIL-STD 883 |

Revision History

| Version | Subjects (major changes since last revision) | Date |
|---------|--|------|
| | | |
| | | |

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